

Characteristic		Symbol	Value	Units
Drain-Source Voltage		V_{DSS}	60	V
Gate-Source Voltage		V_{GSS}	±20	V
Continuous Drain Current (Note 6) V _{GS} = 10V	$T_A = +25^{\circ}C$ $T_A = +100^{\circ}C$	I _D	7.6 5.4	Α
Continuous Drain Current (Note 6) V _{GS} = 4.5V	$T_A = +25^{\circ}C$ $T_A = +100^{\circ}C$	I _D	6.2 4.4	Α
Pulsed Drain Current (10µs pulse, duty cycle = 1%)		I _{DM}	40	A
Maximum Continuous Body Diode Forward Current		Is	1.7	Α
Pulsed Body Diode Forward Current (10µs pulse, duty cycle = 1%)		I _{SM}	40	Α
Avalanche Current, L = 0.1mH		I _{AS}	15.3	Α
Avalanche Energy, L = 0.1mH		E _{AS}	11.7	mJ

Thermal Characteristics (@ $T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5)	P_{D}	1.4	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{ heta JA}$	103	°C/W
Total Power Dissipation (Note 6)	P _D	1.9	W
Thermal Resistance, Junction to Ambient (Note 6)	$R_{ heta JA}$	77	°C/W
Thermal Resistance, Junction to Case	$R_{ heta JC}$	14.5	°C/W
Operating and Storage Temperature Range	T _{J,} T _{STG}	-55 to +175	°C

Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV _{DSS}	60	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 48V$, $V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}		_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V _{GS(TH)}	1	_	2.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance		_	15	19.5	mΩ	$V_{GS} = 10V, I_D = 10A$	
Static Drain-Source On-Resistance	R _{DS(ON)}	_	21	28		$V_{GS} = 4.5V, I_D = 6A$	
Diode Forward Voltage	V_{SD}	_	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	_	864	_		V _{DS} = 30V, V _{GS} = 0V, f = 1MHz	
Output Capacitance	Coss		282		pF		
Reverse Transfer Capacitance	Crss	_	27	_			
Gate Resistance	R_g		1.3	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Qg	_	8.4	_			
Total Gate Charge (V _{GS} = 10V)	Q_g	_	17	_	nC	$V_{DS} = 30V, I_D = 10A$	
Gate-Source Charge	Q_{gs}	_	3.1	_	IIC		
Gate-Drain Charge	Q_{gd}	_	4.3	_			
Turn-On Delay Time	t _{D(ON)}	_	3.4	_		$V_{GS} = 10V, V_{DS} = 30V,$ $R_G = 6\Omega, I_D = 10A$	
Turn-On Rise Time	t _R	_	5.2	_			
Turn-Off Delay Time	t _{D(OFF)}	_	13	_	ns		
Turn-Off Fall Time	t _F	_	7	_			
Reverse Recovery Time	t _{RR}	_	22	_	ns	1 400 11/14 4000/	
Reverse Recovery Charge	Q_{RR}	_	11	_	nC	$I_F = 10A$, di/dt = 100A/ μ s	

lotes: 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.

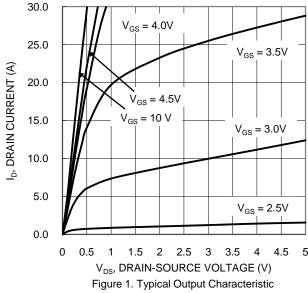
^{6.} Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

^{7.} Short duration pulse test used to minimize self-heating effect.

^{8.} Guaranteed by design. Not subject to product testing.







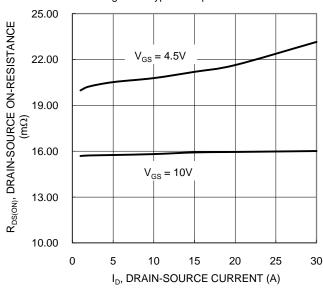


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

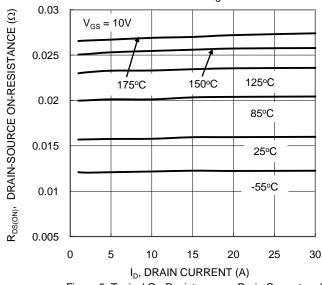
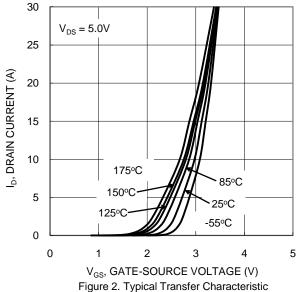


Figure 5. Typical On-Resistance vs. Drain Current and Temperature



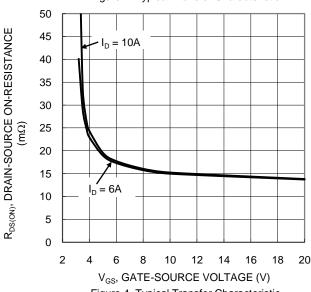


Figure 4. Typical Transfer Characteristic

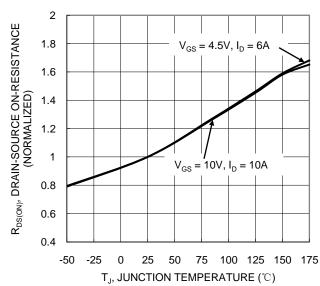


Figure 6. On-Resistance Variation with Temperature





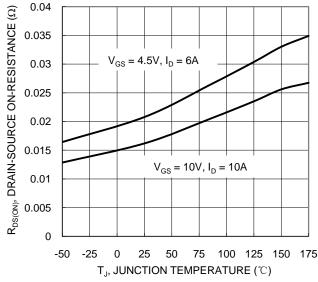


Figure 7. On-Resistance Variation with Temperature

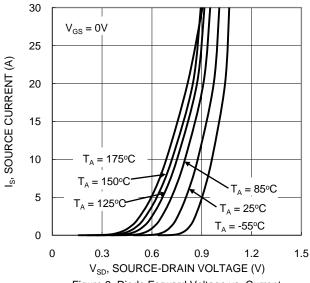


Figure 9. Diode Forward Voltage vs. Current

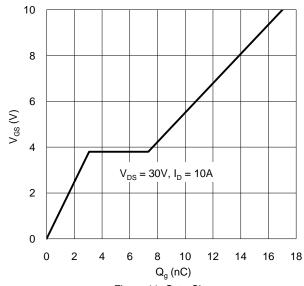


Figure 11. Gate Charge

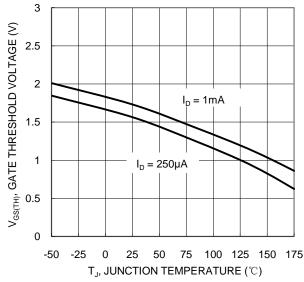
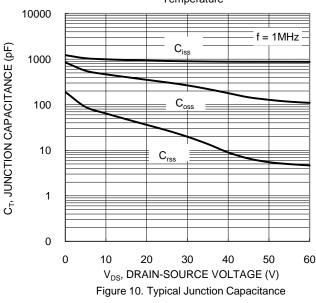


Figure 8. Gate Threshold Variation vs. Junction Temperature



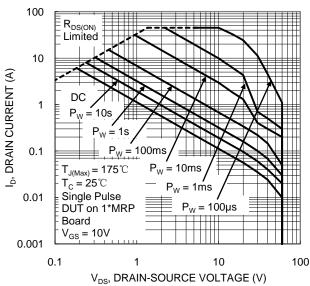


Figure 12. SOA, Safe Operation Area



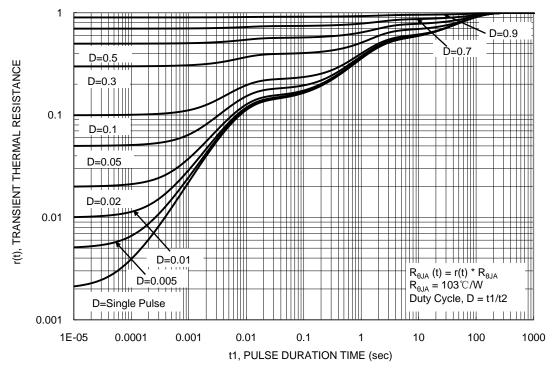


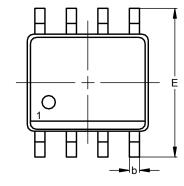
Figure 13. Transient Thermal Resistance

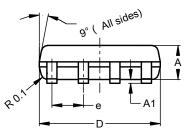


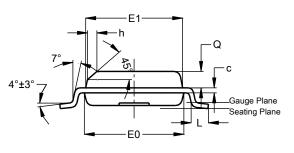
Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8





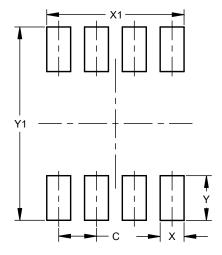


SO-8				
Dim	Min	Max	Тур	
Α	1.40	1.50	1.45	
A1	0.10	0.20	0.15	
b	0.30	0.50	0.40	
C	0.15	0.25	0.20	
D	4.85	4.95	4.90	
Е	5.90	6.10	6.00	
E1	3.80	3.90	3.85	
E0	3.85	3.95	3.90	
е			1.27	
h	-		0.35	
L	0.62	0.82	0.72	
Q	0.60	0.70	0.65	
All Dimensions in mm				

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



Dimensions	Value (in mm)
C	1.27
Х	0.802
X1	4.612
Y	1.505
Y1	6.50



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